

Content

Author.....	4
1 Introduction	5
2 Brief overview of SIMS.....	7
2.1 Basics of SIMS.....	7
2.2 Phenomenon of sputtering	9
3 Applications of SIMS method	11
3.1 Depth profiling.....	11
3.2 Quantitative analysis	19
3.3 2D imaging	20
3.4 3D depth profiling by TOF-SIMS	25
3.5 FIB-SIMS tomography and correlative analysis	27
4 Conclusion.....	31
References	33
Abstract (eng).....	36
Abstrakt (cz).....	36